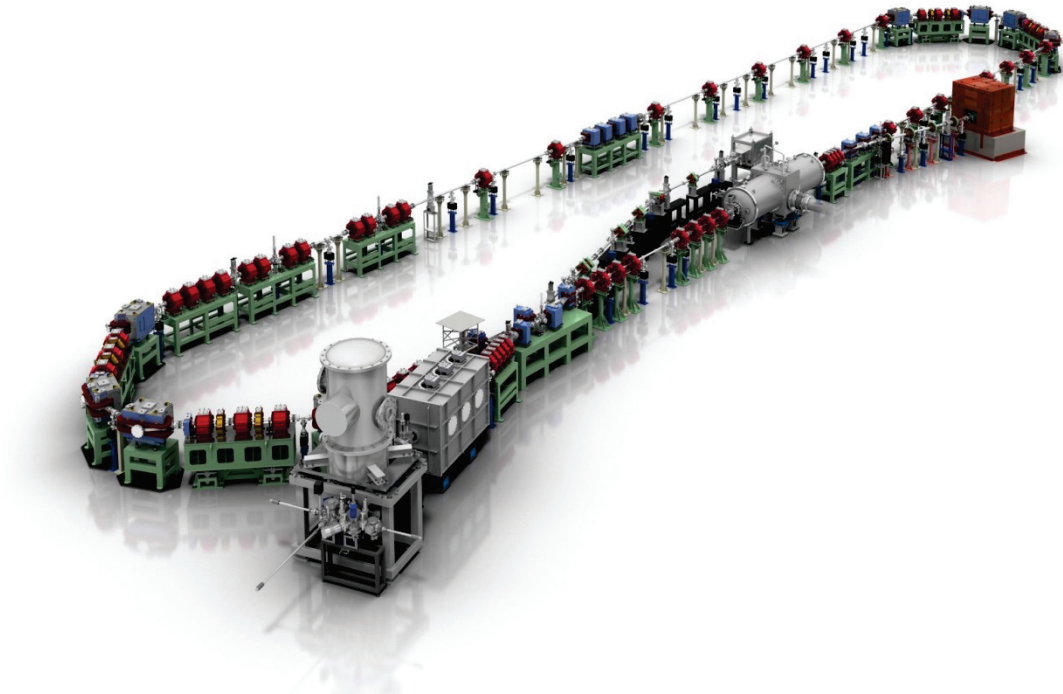




Performance of the Digital LLRF Systems for cERL at KEK

Feng QIU (KEK) June 10, 2015



ERL2015, Stony Brook, NY USA. June 7-12, 2015

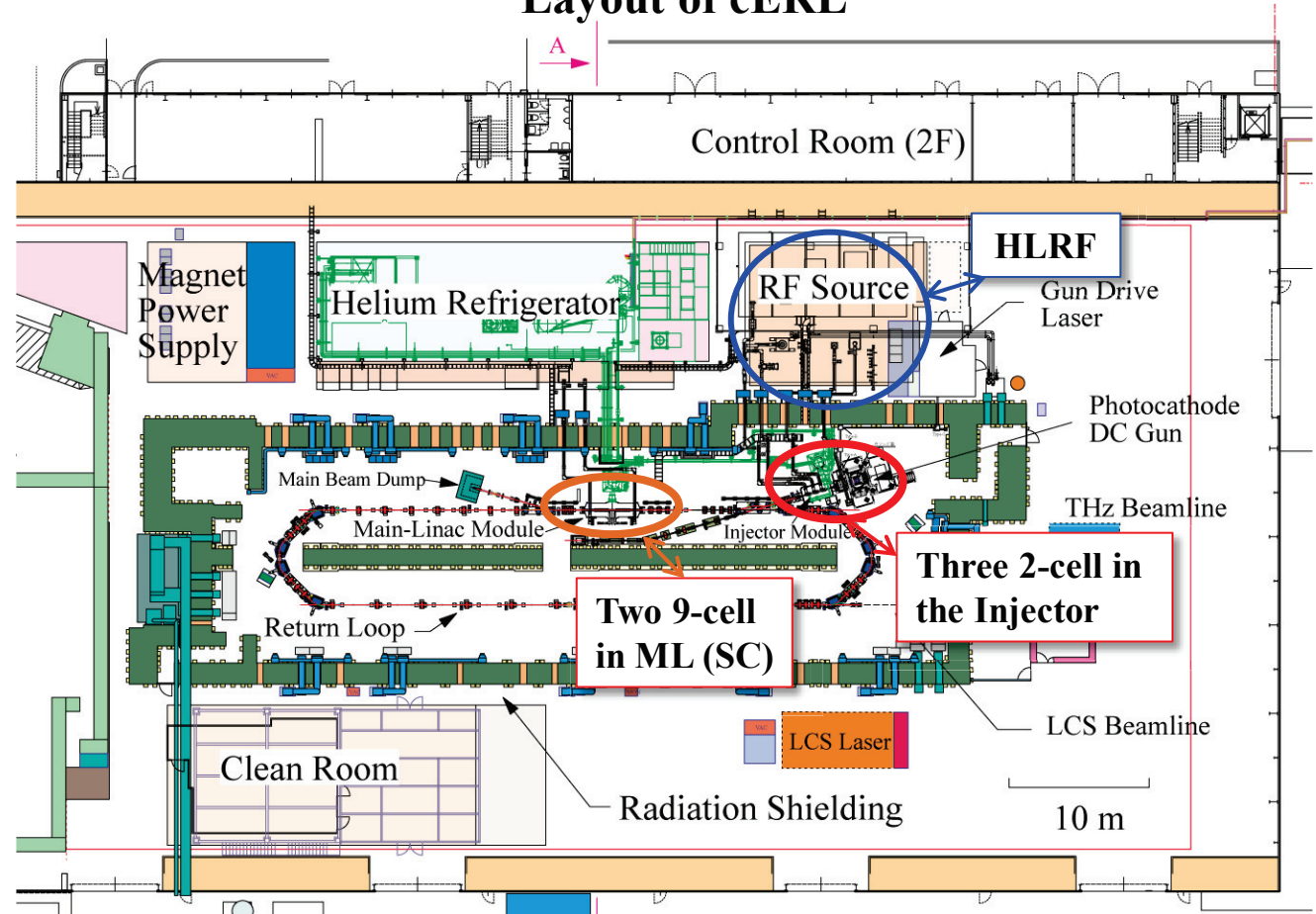
Main Content

- Introduction
- High Level RF system
- Low Level RF system
- Performance
- Disturbances in RF system
- Adaptive feedforward control
- Summary

Introduction

- Compact ERL (cERL) is a test facility for the future 3-GeV ERL project. It is a 1.3-GHz superconducting system and is operated in CW mode.

Layout of cERL



Injector consists of four cavities: Buncher (NC), Injector 1 (SC), Injector 2 (SC), Injector 3 (SC).

Main linac includes two nine-cell cavities (SC).

Two 9-cell in ML (SC)

Three 2-cell in the Injector

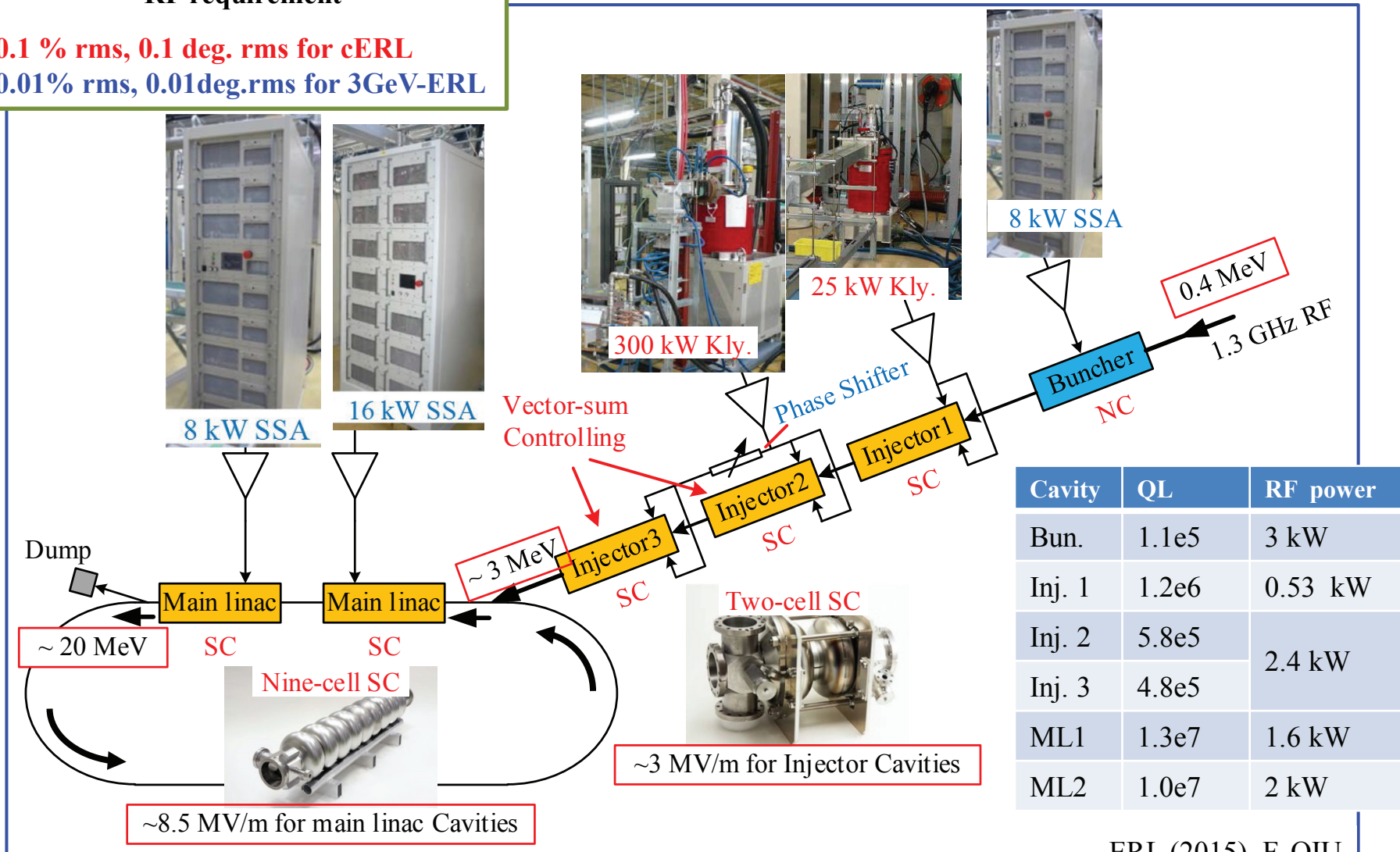
- April, 2013, injector commissioning. Oct. 2013, main linac commissioning.

HLRF (Power Source)

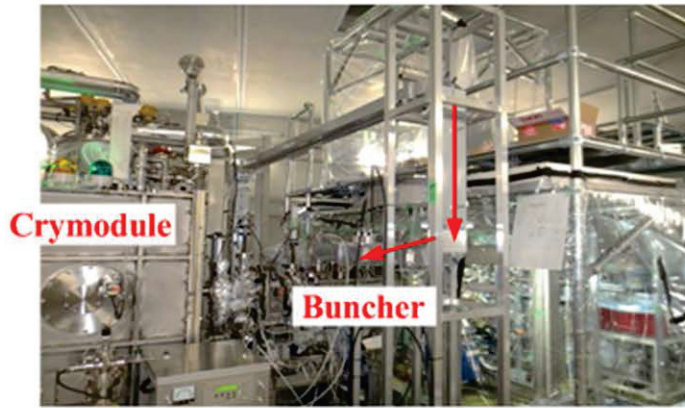
■ At present, total four kinds of Power Sources are applied in cERL : 8-kW SSA, 16-kW SSA, 25-kW Klystron and 300 kW Klystron.

RF requirement

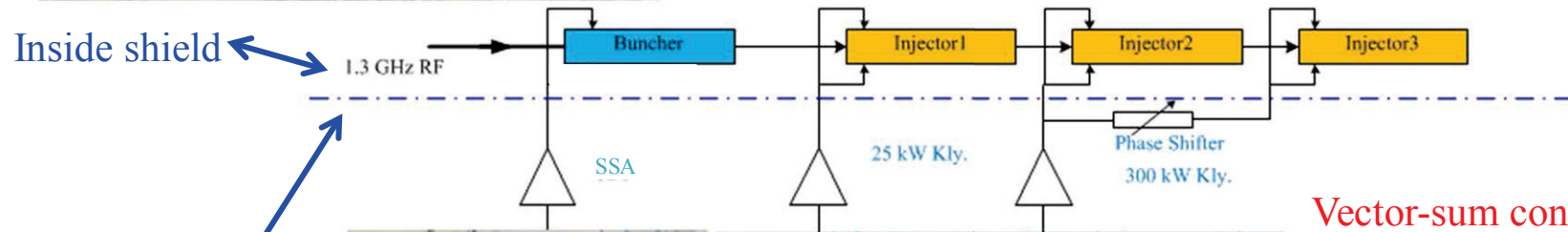
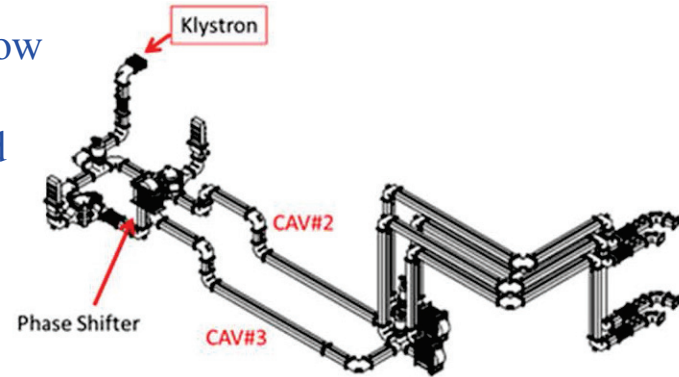
0.1 % rms, 0.1 deg. rms for cERL
0.01% rms, 0.01deg.rms for 3GeV-ERL



HLEF (Power Distribution System)

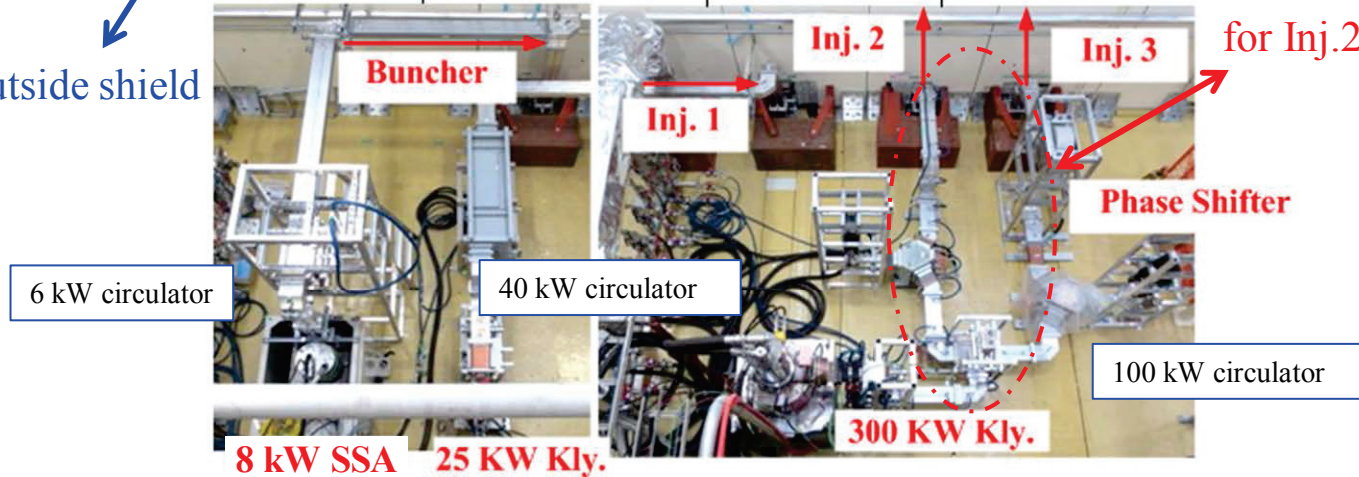


Rather narrow space and complicated waveguide.

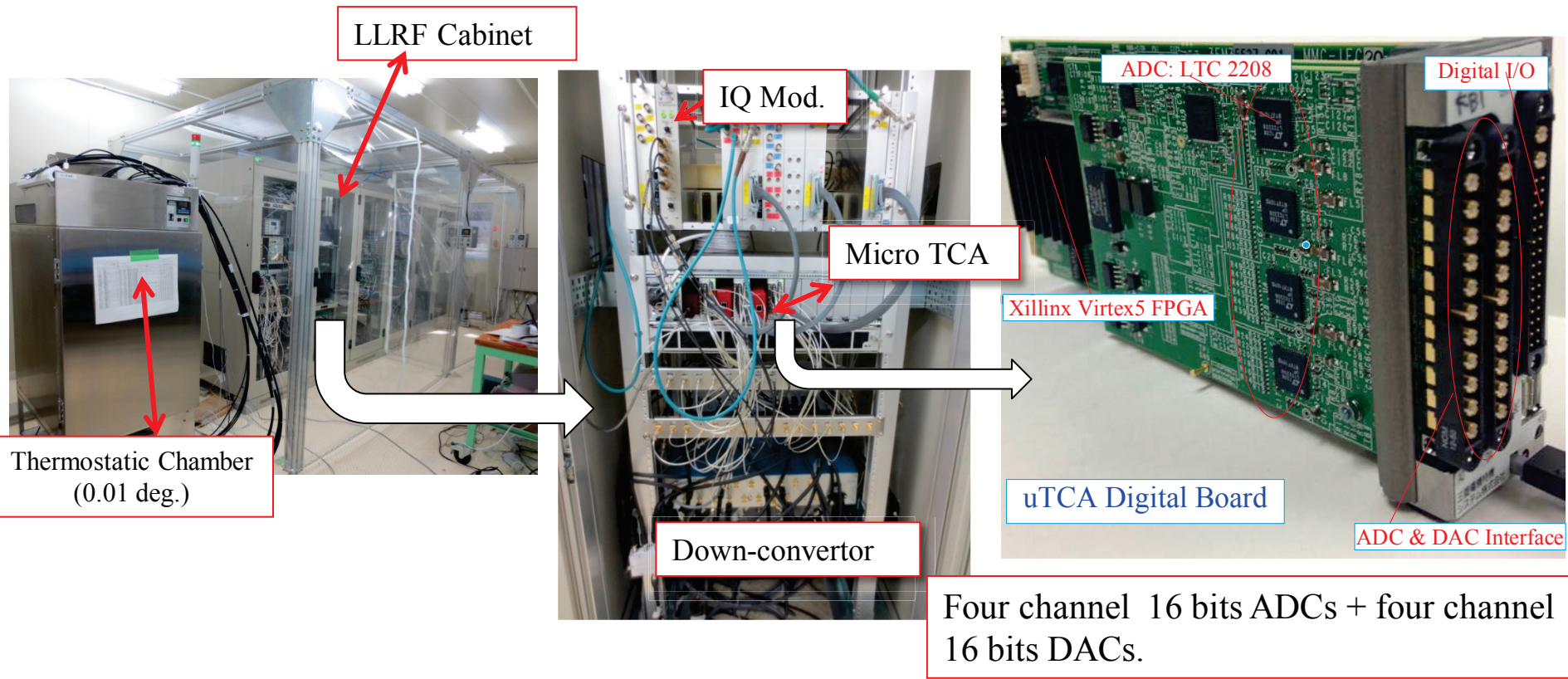


Inside shield
Outside shield

Vector-sum controlling for Inj. 2 and Inj. 3.



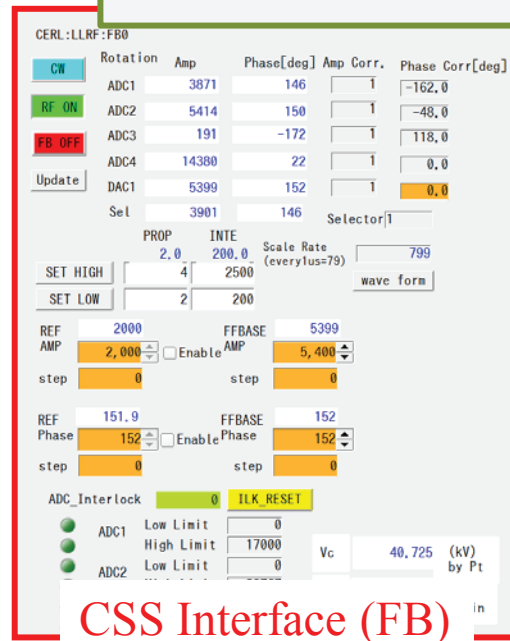
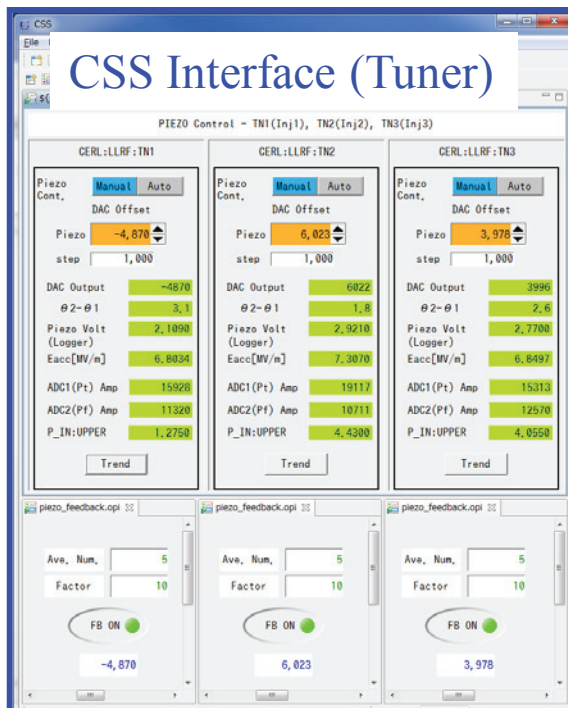
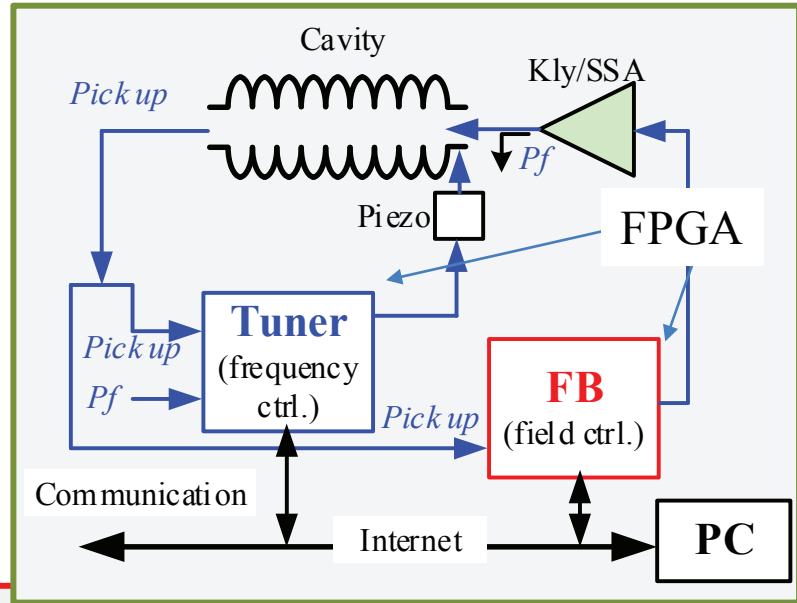
LLRF (Digital Board)



Digital Board	type	Feature
ADC	LTC2208	16 bits, 130 MHz (Max.)
DAC	AD9783	16 bits, 500 MHz (Max.)
FPGA	Virtex 5 FX	550 MHz (Max.), includes a Power PC with Linux, EPICS is installed on the Linux.

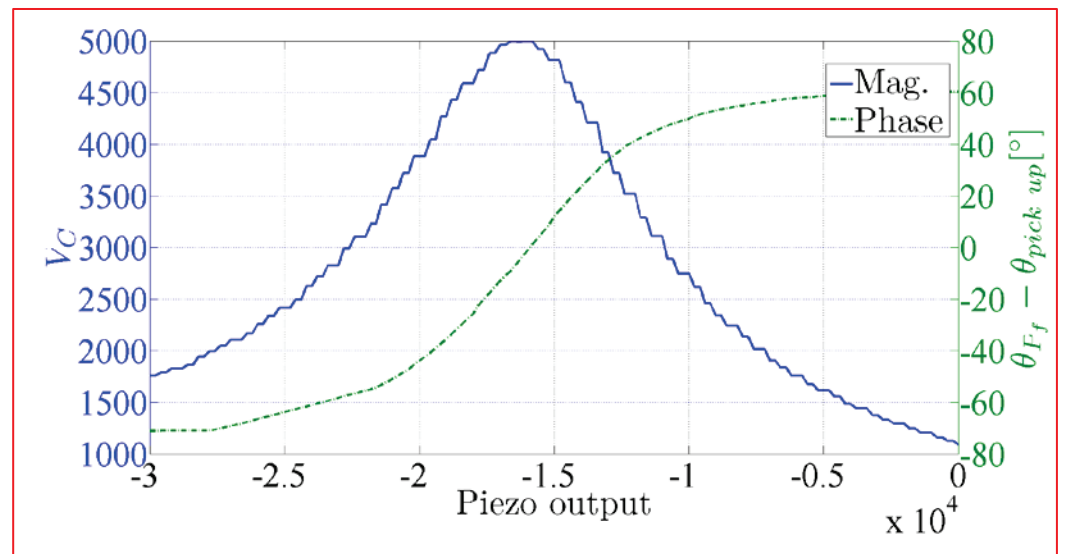
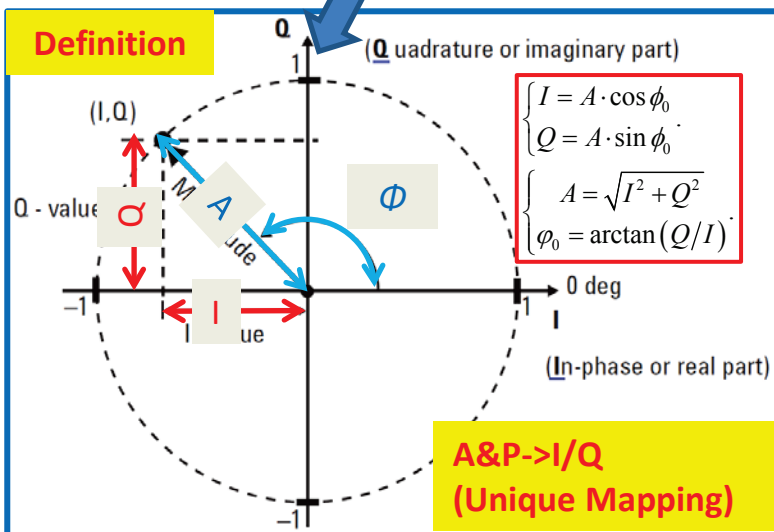
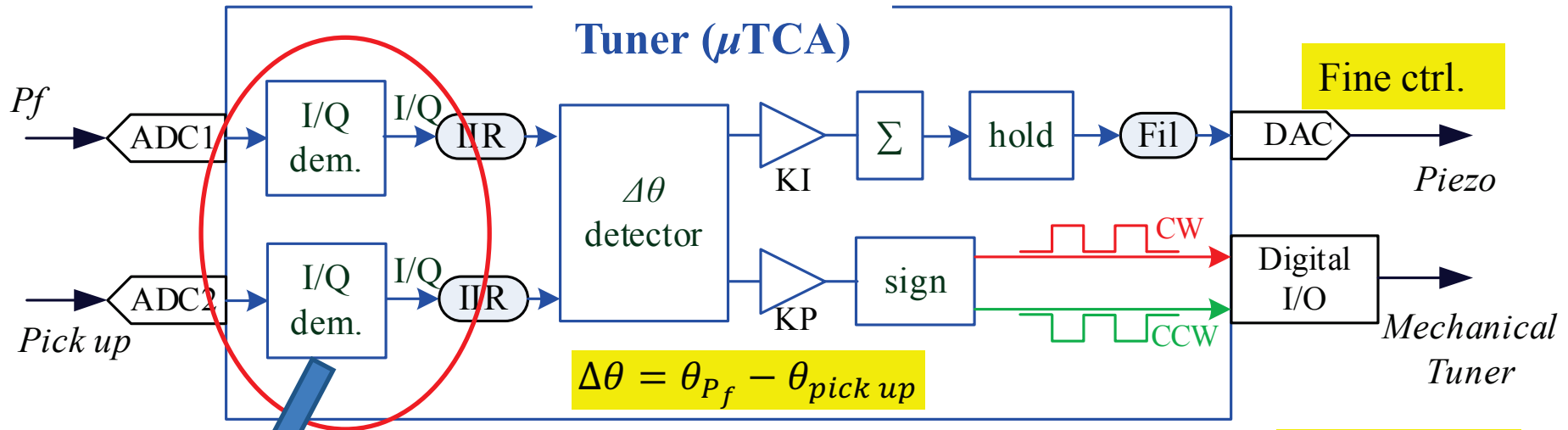
LLRF (DAQ & communication)

- LLRF (Tuner + FB)
- EPICS (Experimental Physics and Industrial Control System) is installed inside Micro TCA and is used as the DAQ (data acquisition) system.
- CSS (Control System Studio) is in charge of the user interface programming.

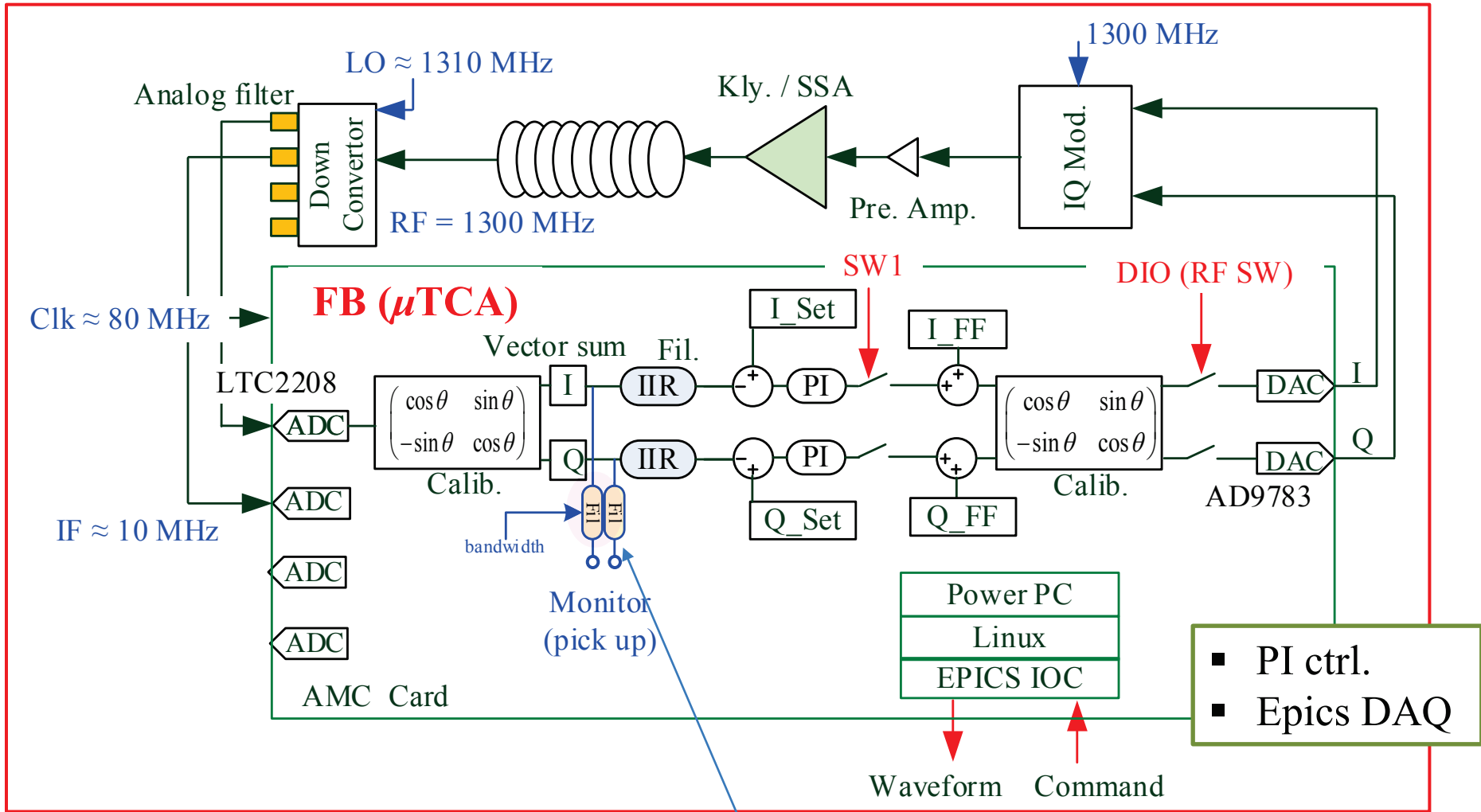


LLRF (frequency control)

- Cavity resonance frequency control: Tuner + Piezo.



LLRF (field control)

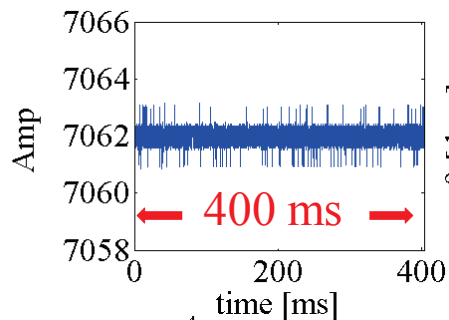


$$IIR: y(n) = \alpha \cdot x(n) + (1 - \alpha) \cdot y(n-1), \alpha \ll 1$$

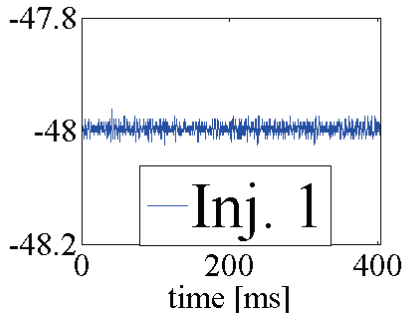
Current Performance (RF field)



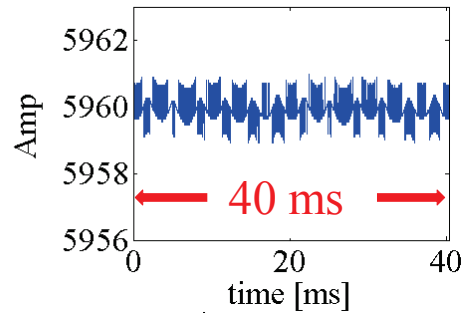
Amp.



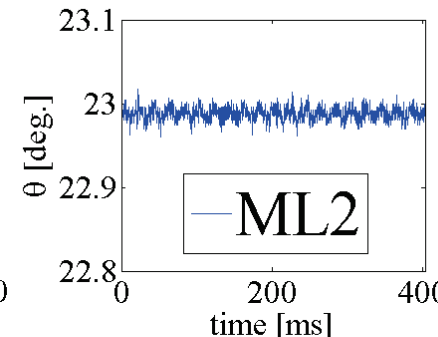
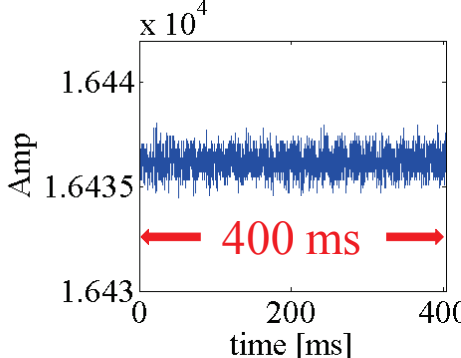
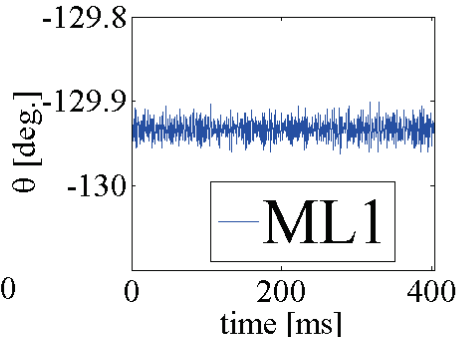
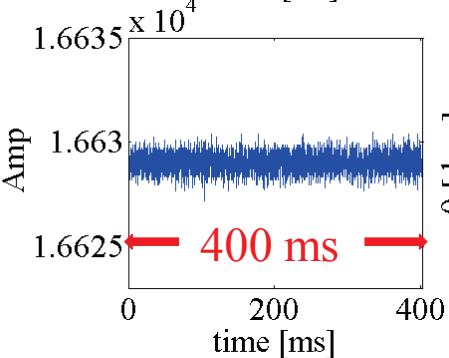
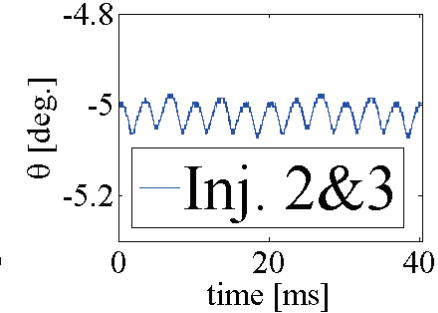
Pha.



Amp.



Pha.

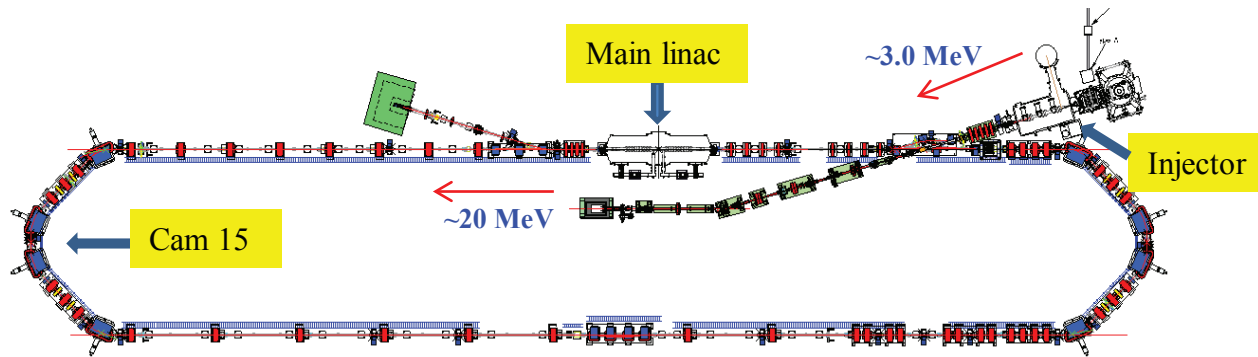


RF stability	Bun.	Inj. 1	Inj. 2&3 (VS)	ML1	ML2
$\Delta A/A$ [% .rms]	0.07%	0.006%	0.007%	0.003%	0.003%
$\Delta \theta$ [° .rms]	0.04°	0.009°	0.025°	0.010°	0.007°

Beam Momentum jitter is 0.006% (in agreement)

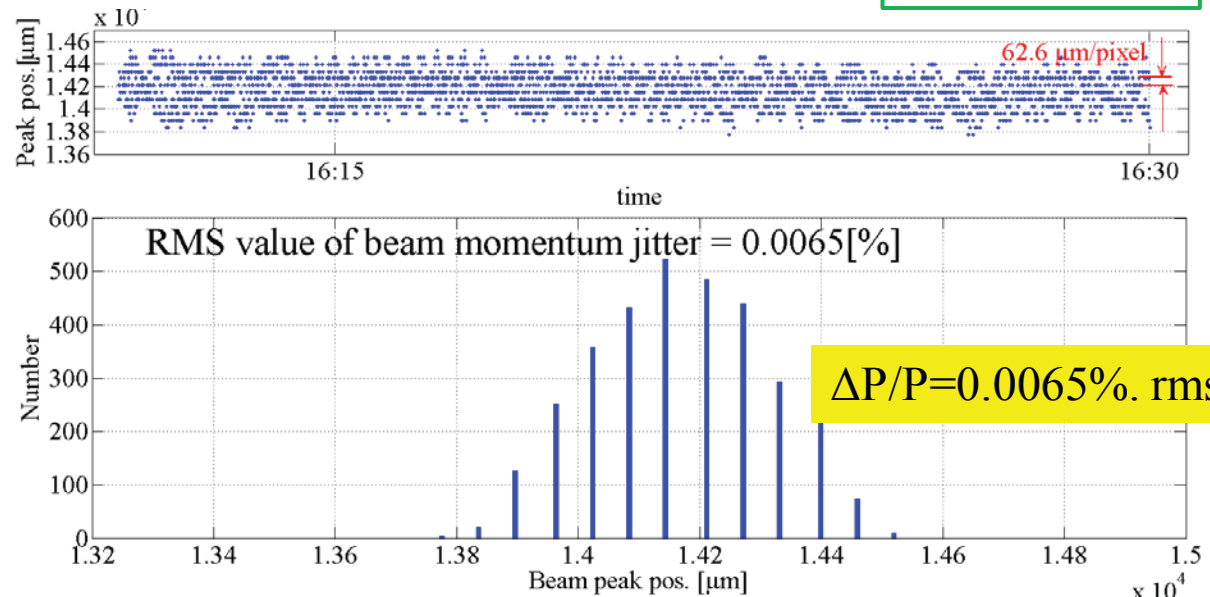
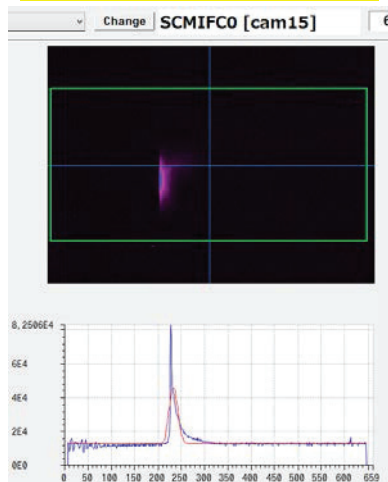
Performance (Beam energy)

- Beam momentum jitter is measured by screen monitor and determined by the peak point of the projection of the screen.



Dispersion
 $\eta=2.2\text{m}$
Resolution
 $62.6 \mu\text{m}/\text{pixel}$

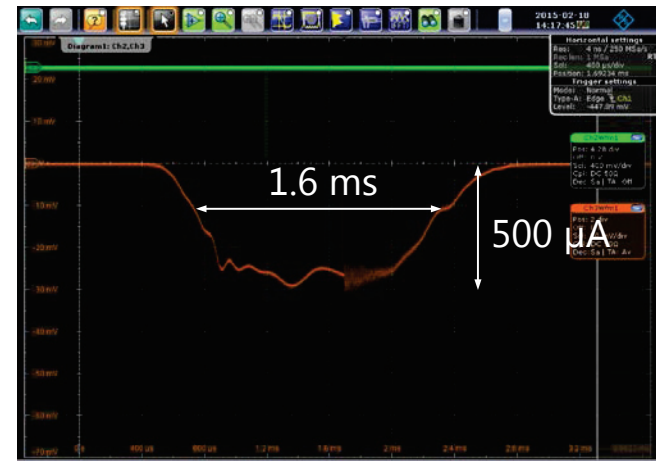
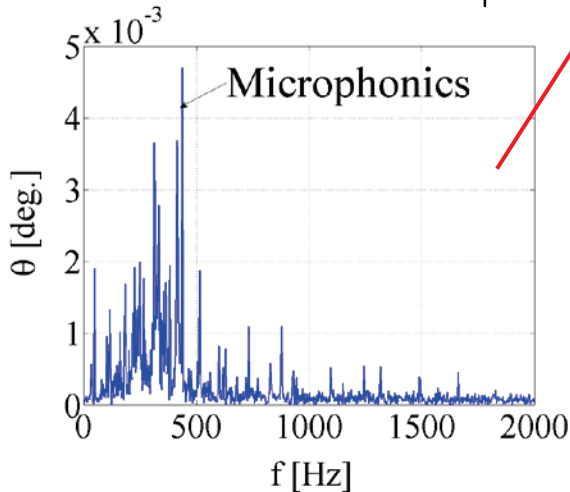
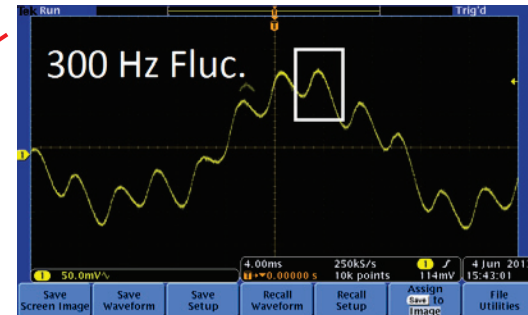
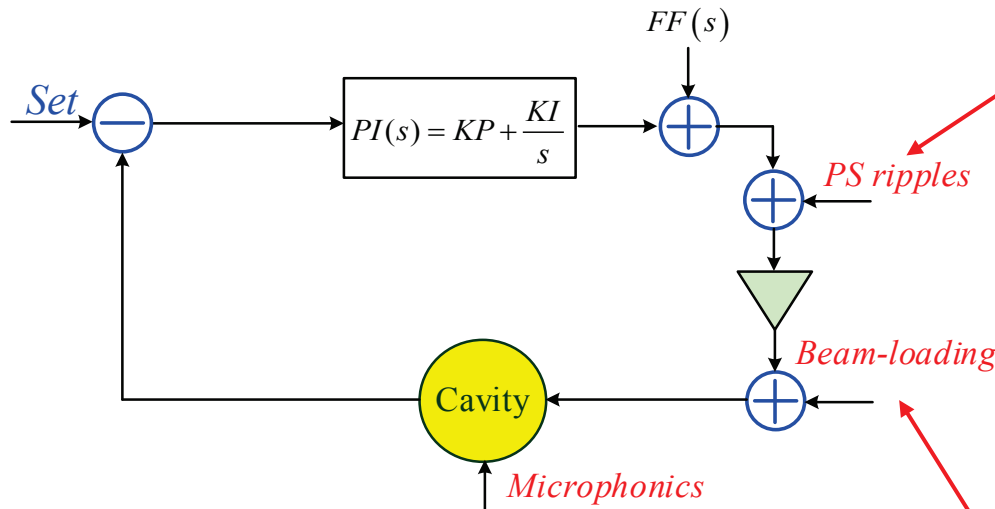
Screen monitor



R&D (Adaptive FF)

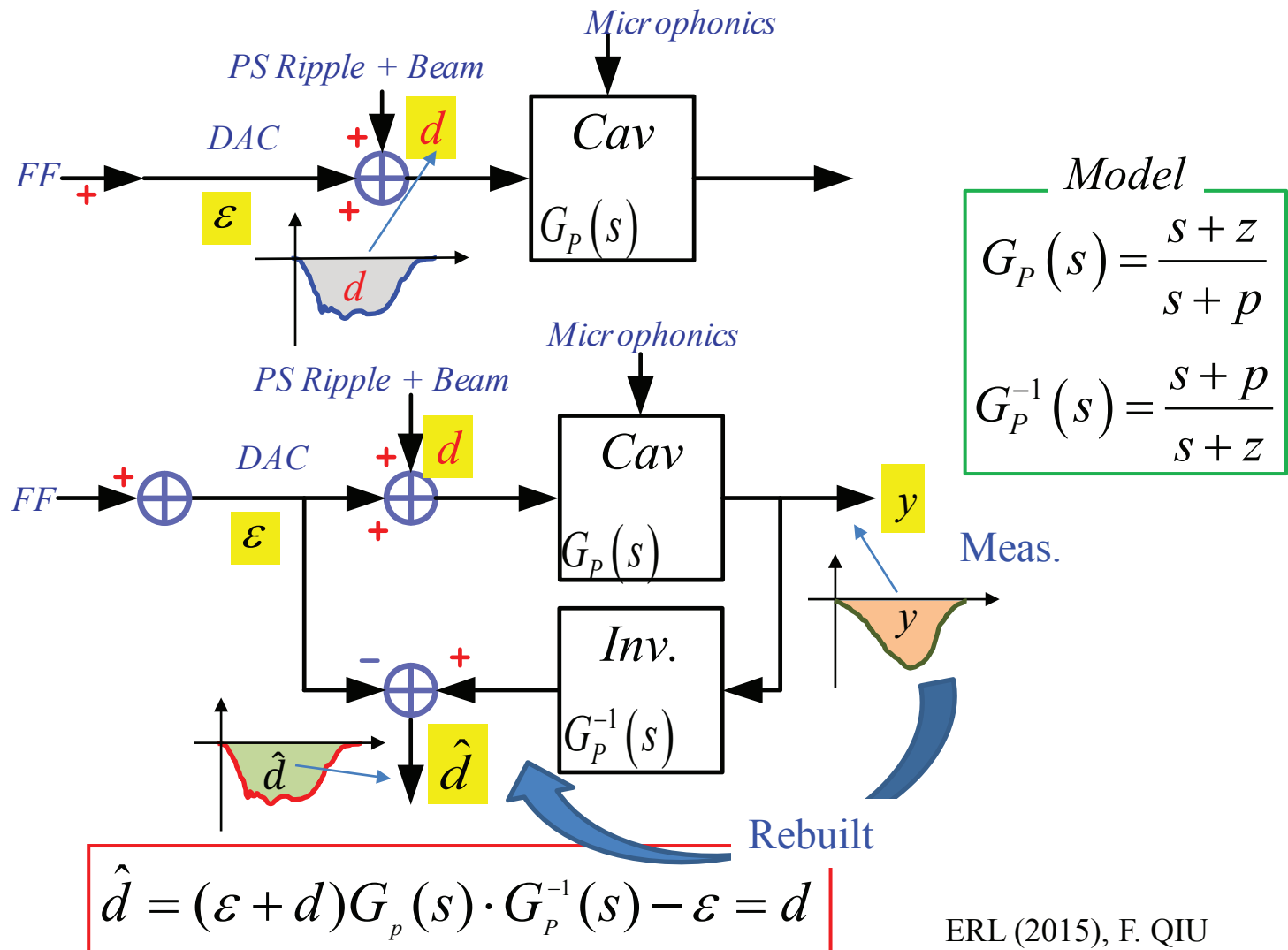
Disturbances in RF system

■ Main disturbances: High voltage power supply ripples (300 Hz) + burst mode beam-loading (0.5 mA~1mA, 1 ms ~ 2 ms) and Microphonics (DC ~ 500 Hz).



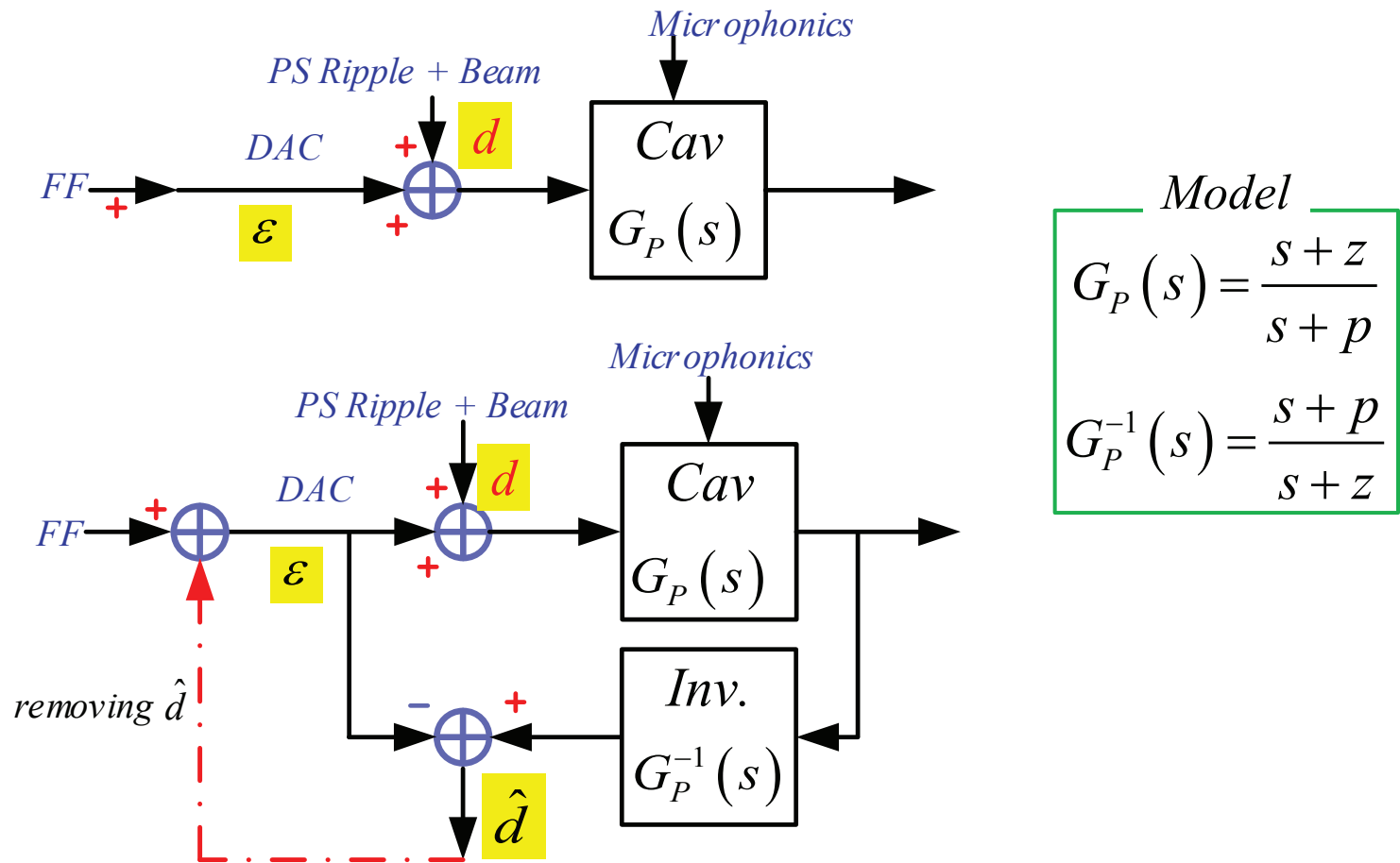
Adaptive FF ctrl

- The disturbances estimate \hat{d} can be evaluated accurately if we “know” the mathematical model of the system (disturbance observer).
- Disturbance-Observer-Based control (DOB control)



Adaptive FF ctrl (cont'd)

- The disturbance estimate \hat{d} can be removed from FF table, thus the disturbance signal d is rejected.



Model

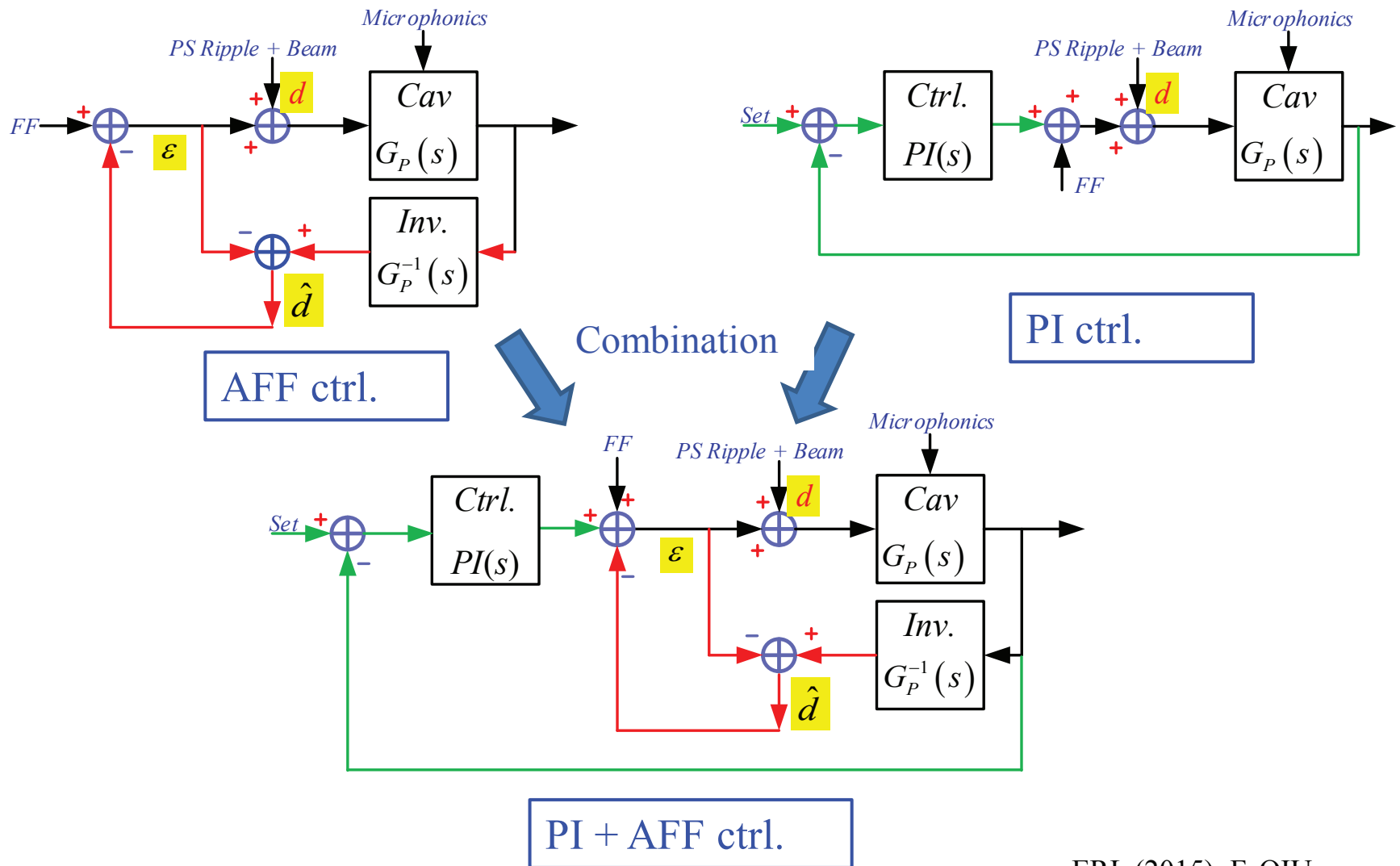
$$G_P(s) = \frac{s + z}{s + p}$$

$$G_P^{-1}(s) = \frac{s + p}{s + z}$$

$$\hat{d} = (\epsilon + d)G_P(s) \cdot G_P^{-1}(s) - \epsilon = d$$

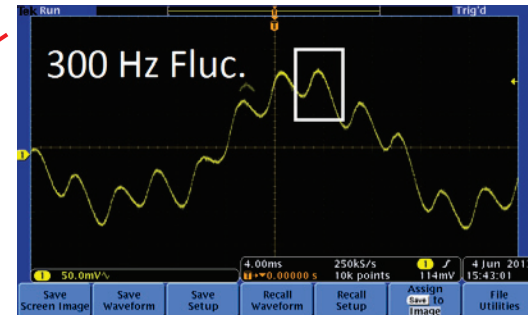
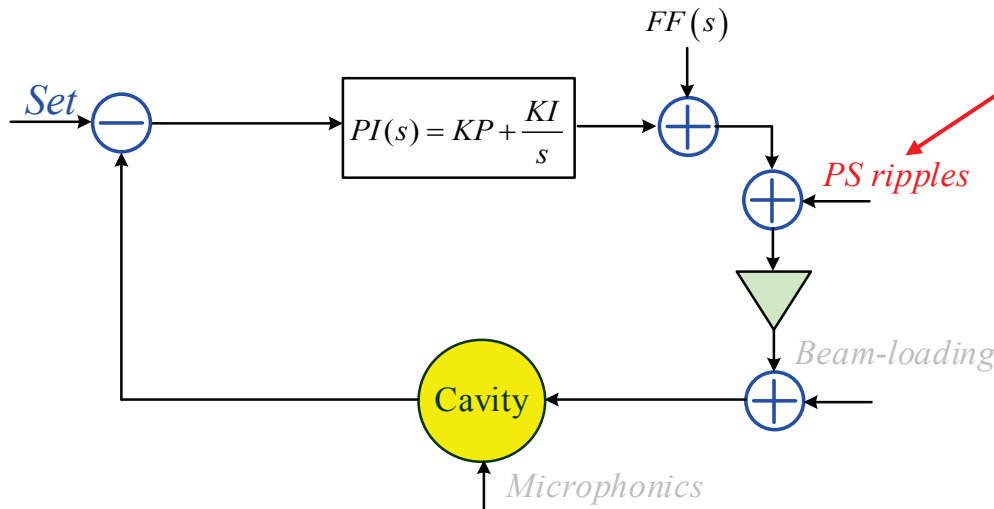
Adaptive FF ctrl (cont'd)

- In practical, the combination of AFF control and PI control.



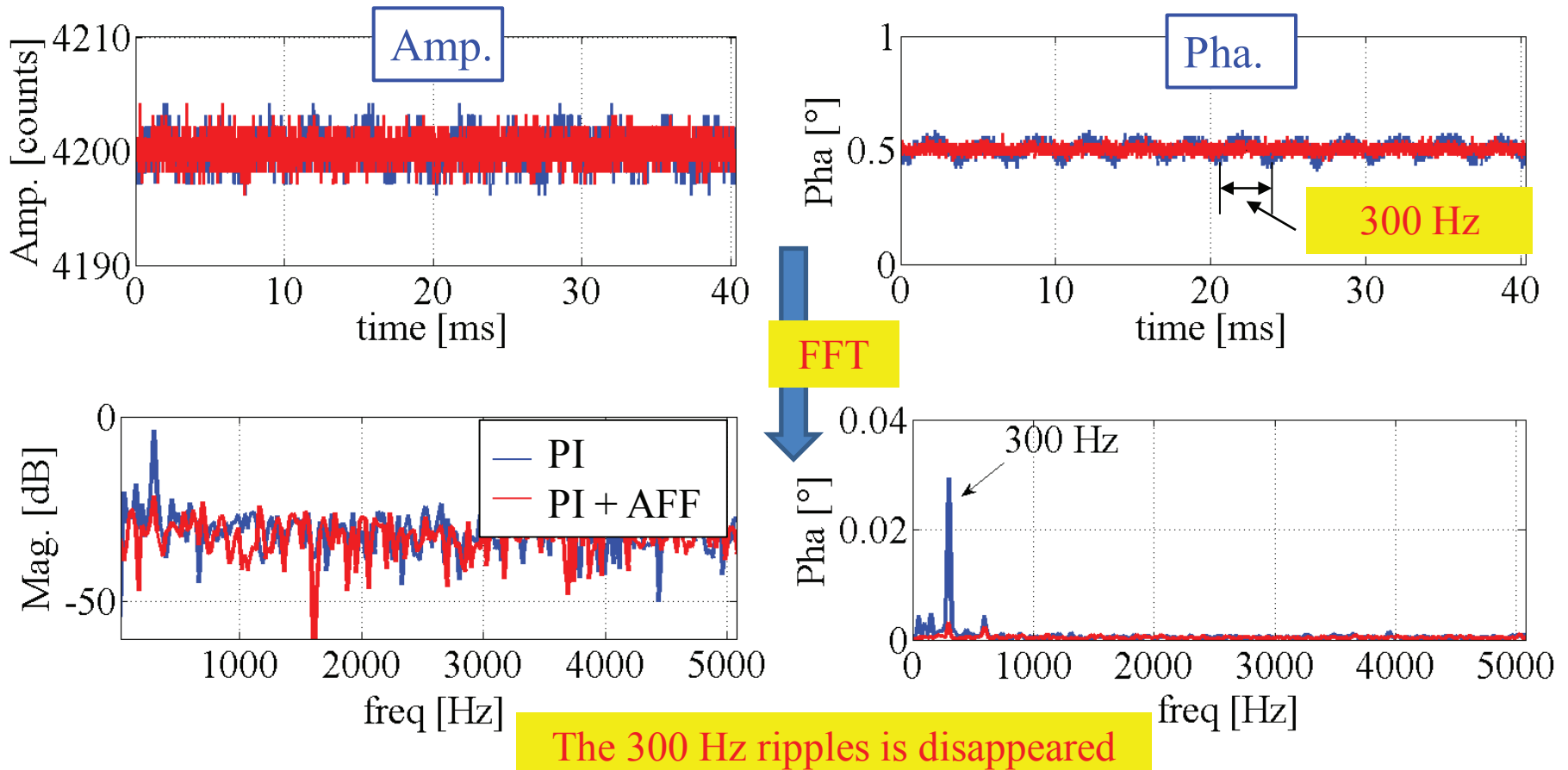
Disturbances 1 (HVPS ripples)

■ Main disturbances: High voltage power supply ripples (300 Hz) + burst mode beam-loading (0.5 mA~1mA, 1 ms ~ 2 ms) and Microphonics (DC ~ 500 Hz).



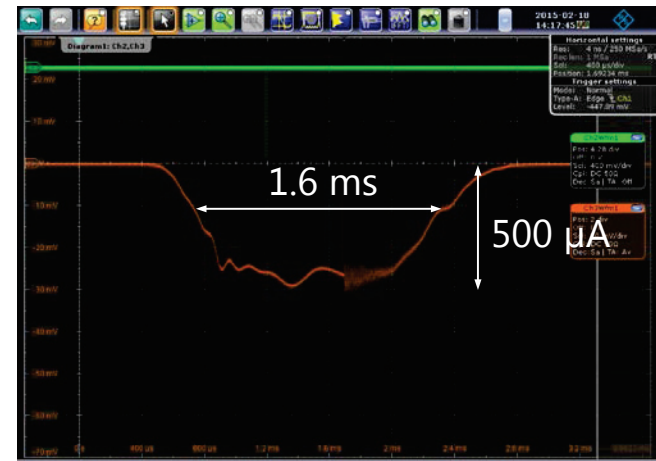
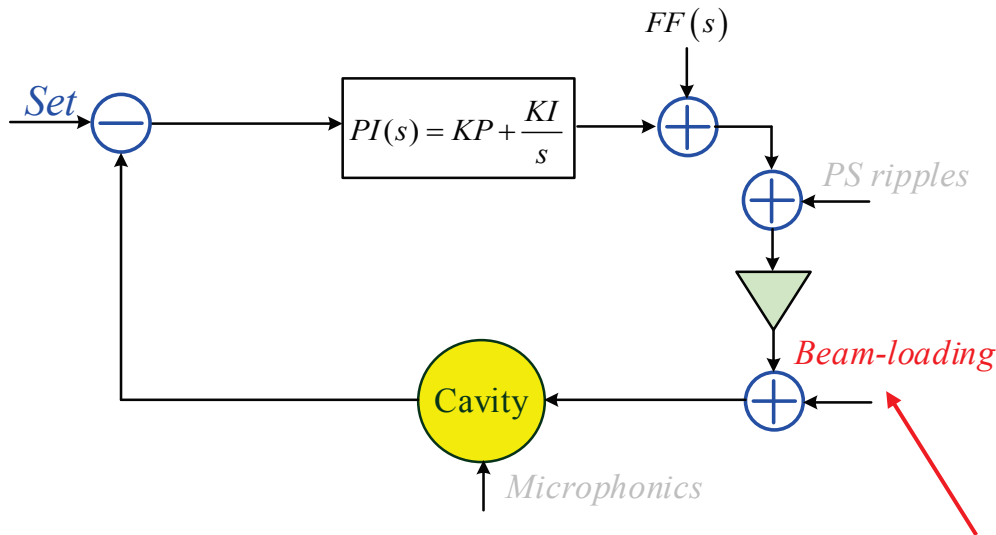
Application 1 (HVPS ripples)

- Disturbances: high voltage power supply ripples (300 Hz ripples).



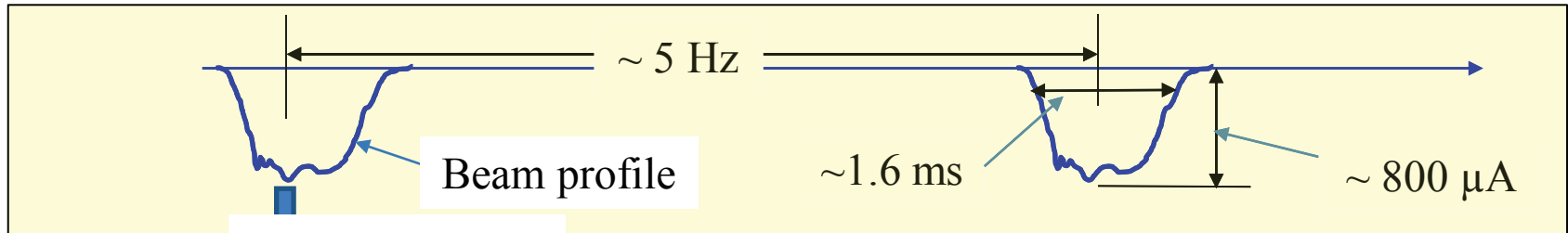
Disturbances 2 (beam-loading)

■ Main disturbances: High voltage power supply ripples (300 Hz) + burst mode beam-loading (0.5 mA~1mA, 1 ms ~ 2 ms) and Microphonics (DC ~ 500 Hz).

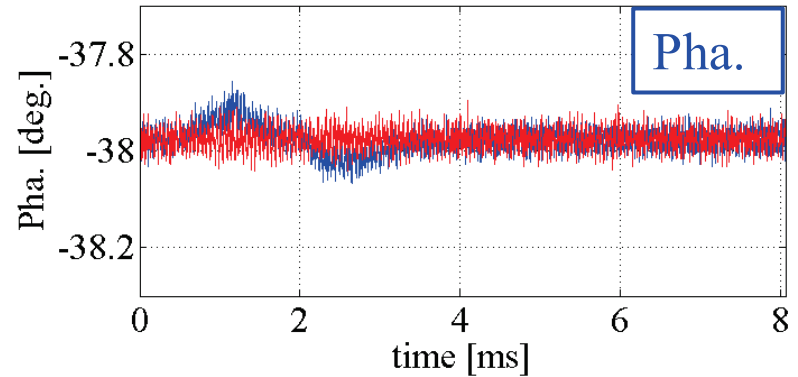
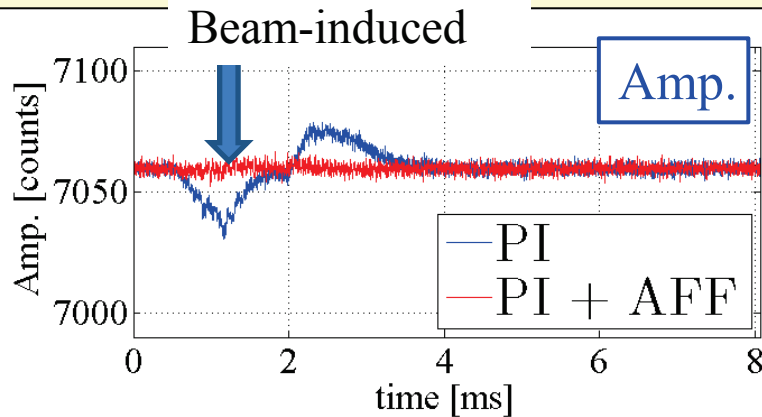


Application 2 (Beam-loading)

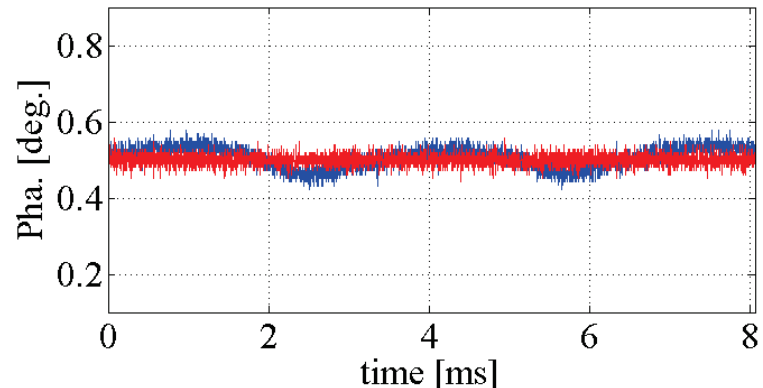
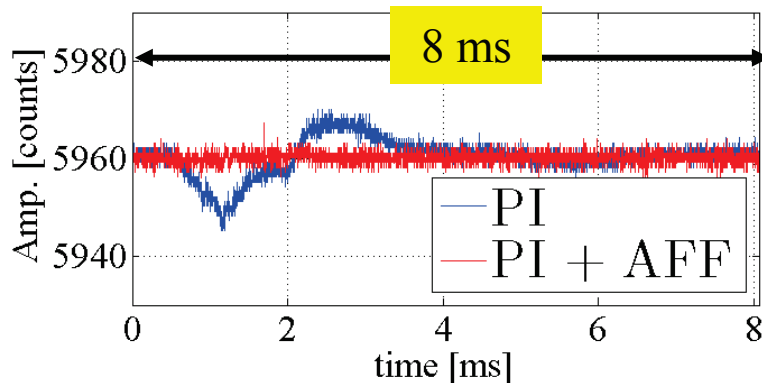
- Disturbances: Beam-loading (about 1.6 ms and 800 μA beam current)



Inj. 1

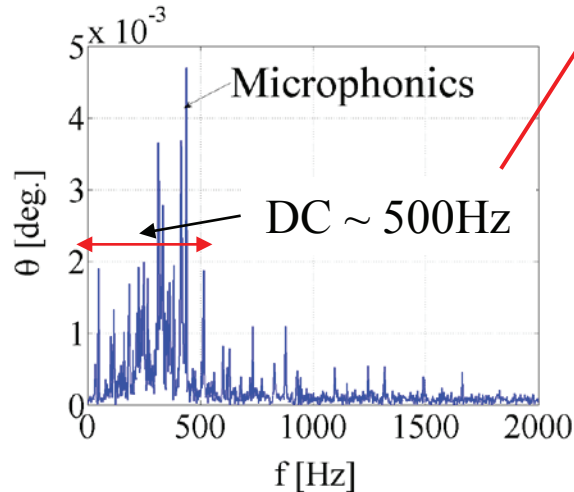
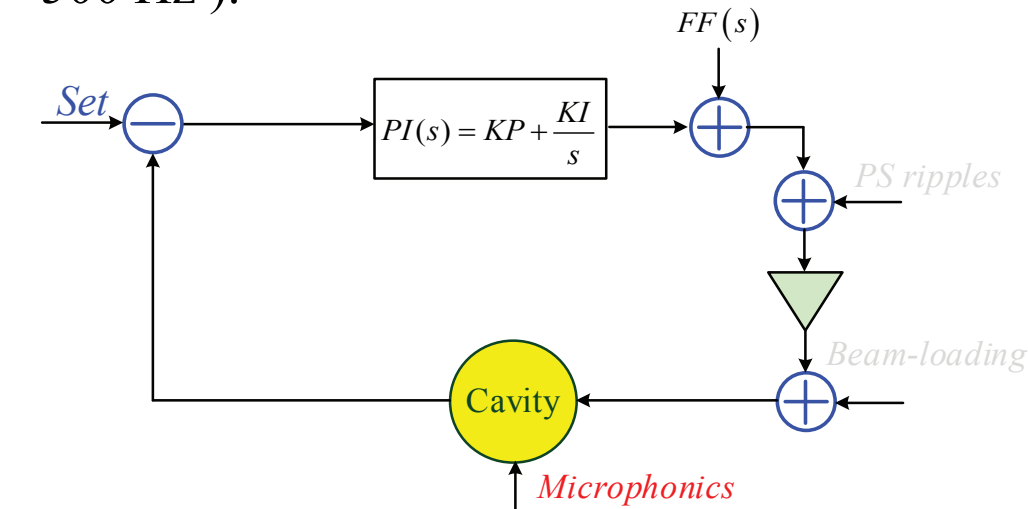


Inj. 2&3



Disturbances 3 (Microphonics)

■ Main disturbances: High voltage power supply ripples (300 Hz) + burst mode beam-loading (0.5 mA~1mA, 1 ms ~ 2 ms) and Microphonics (DC ~ 500 Hz).

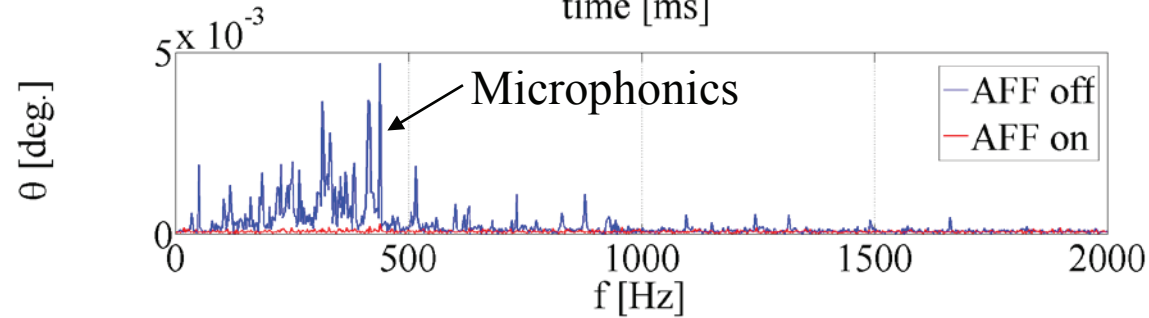
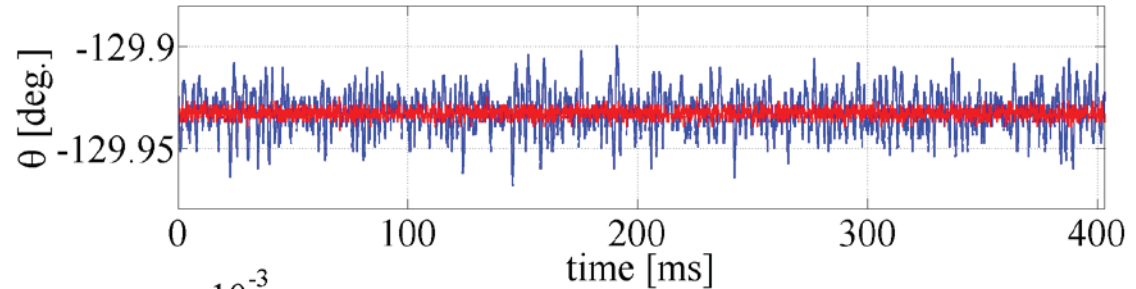


Application 3 (Microphonics)

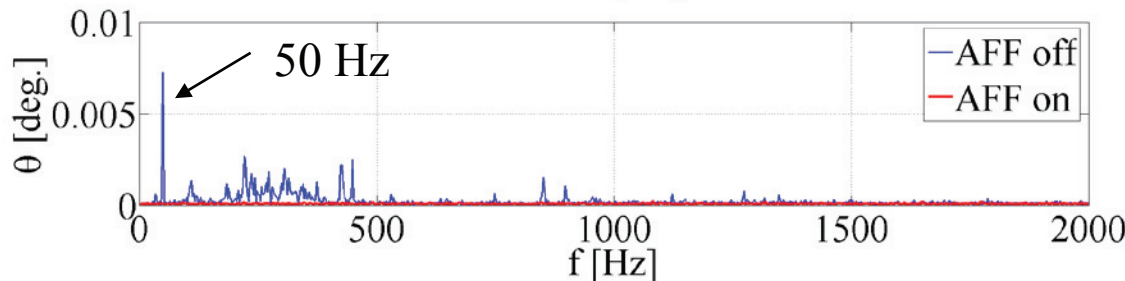
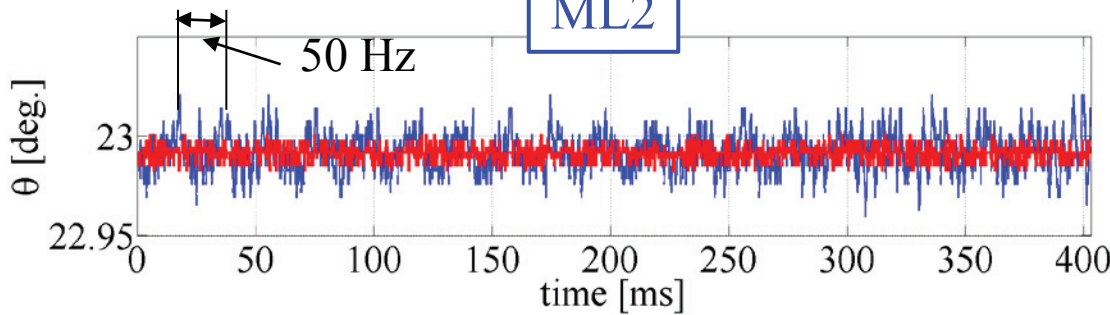
■ Disturbances: Microphonics (DC ~ 500 Hz)

■ Even with high feedback gains, the microphonics still exist in the measured RF field.

ML1



ML2



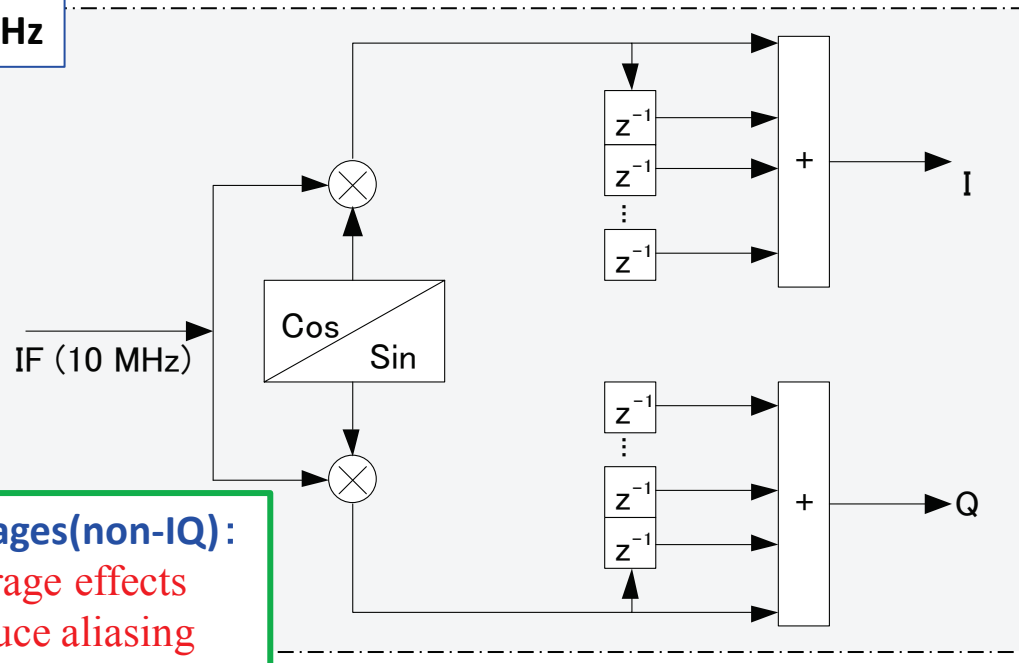
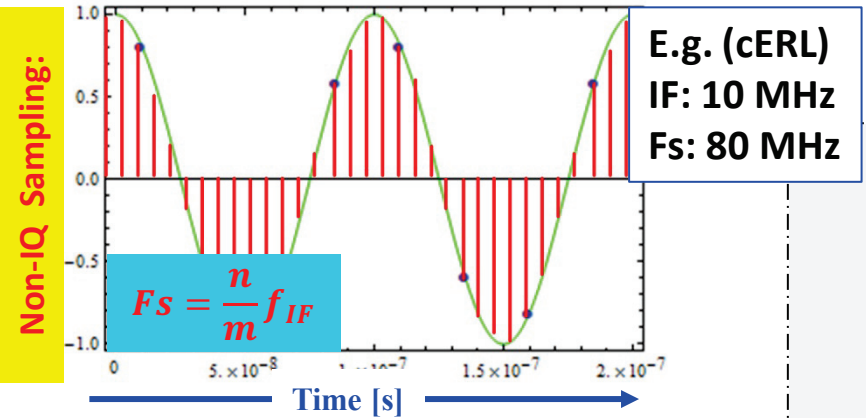
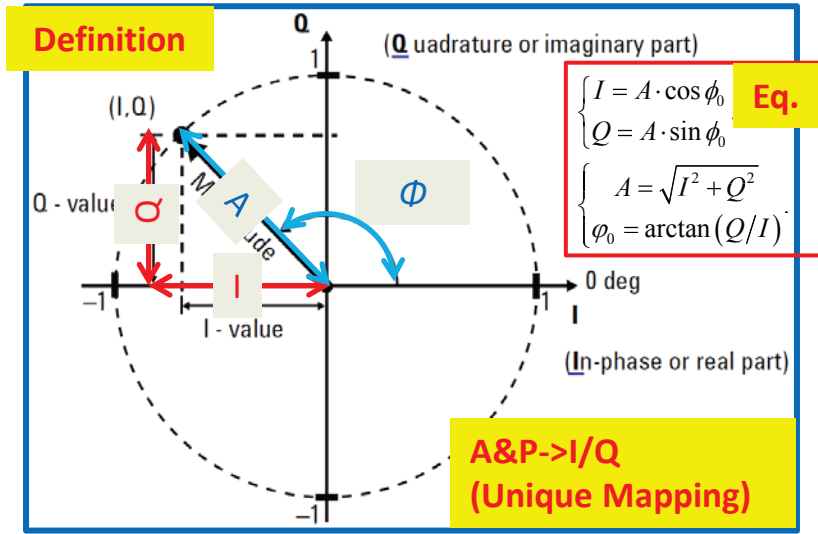
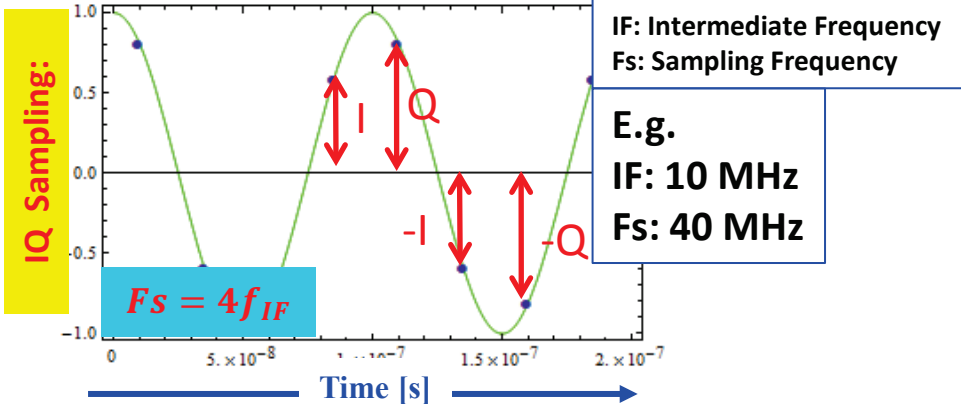
The 50 Hz component is disappeared

Summary

- Construction of the RF system for cERL was finished
- RF field requirement is satisfied.
- Very good beam momentum.
- Disturbances in RF system is rejected by a new AFF control approach

Back up

DSP algorithms (I/Q detection)



$$I = \frac{2}{8} \cdot \sum_{k=0}^7 y_i \cdot \cos(k \cdot \frac{2\pi}{8})$$

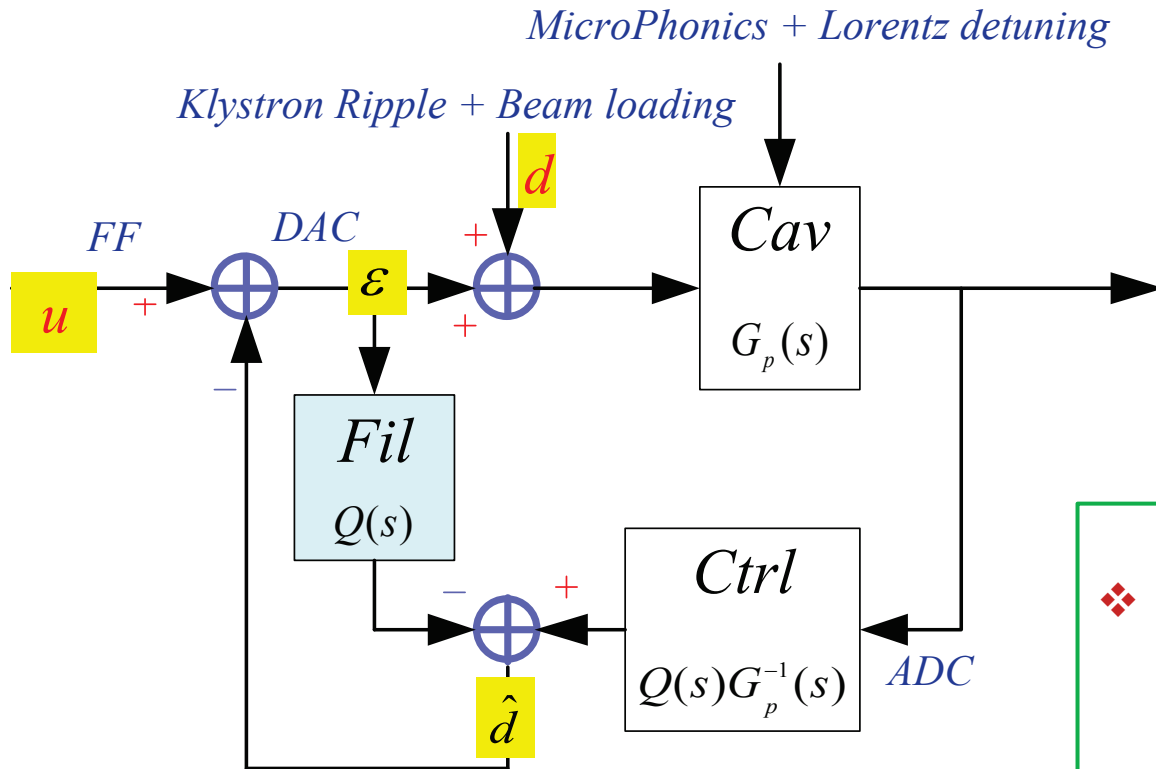
$$Q = \frac{2}{8} \cdot \sum_{k=0}^7 y_i \cdot \sin(k \cdot \frac{2\pi}{8})$$

- Advantages(non-IQ):**
- Average effects
 - Reduce aliasing

Model Based FB optimization



- The “Q” filter (LP filter) is used for improving the robustness (remove the high frequency noises)?



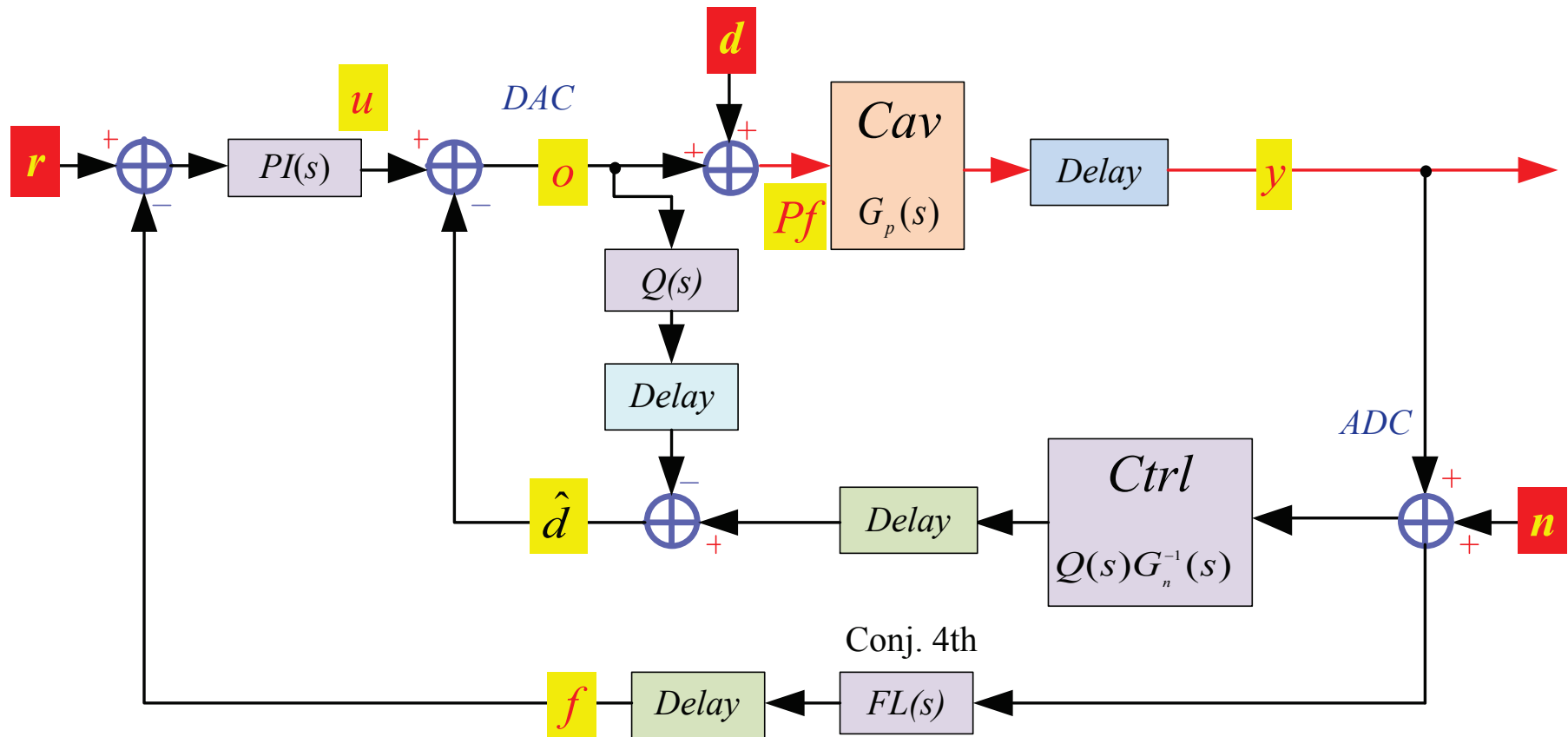
- Tips*
- ❖ Connected another system $Q(s)$ with $G_p^{-1}(s)$ to make sure it can be physically realized.
 - ❖ If the $Q(s)$ is an low-pass filter, then the d can be still evaluated.

$$\hat{d} = (\varepsilon + d)G_p(s) \cdot G_p^{-1}(s) \cdot Q(s) - \varepsilon \cdot Q(s) = d \cdot Q(s)$$

Total LLRF diagram



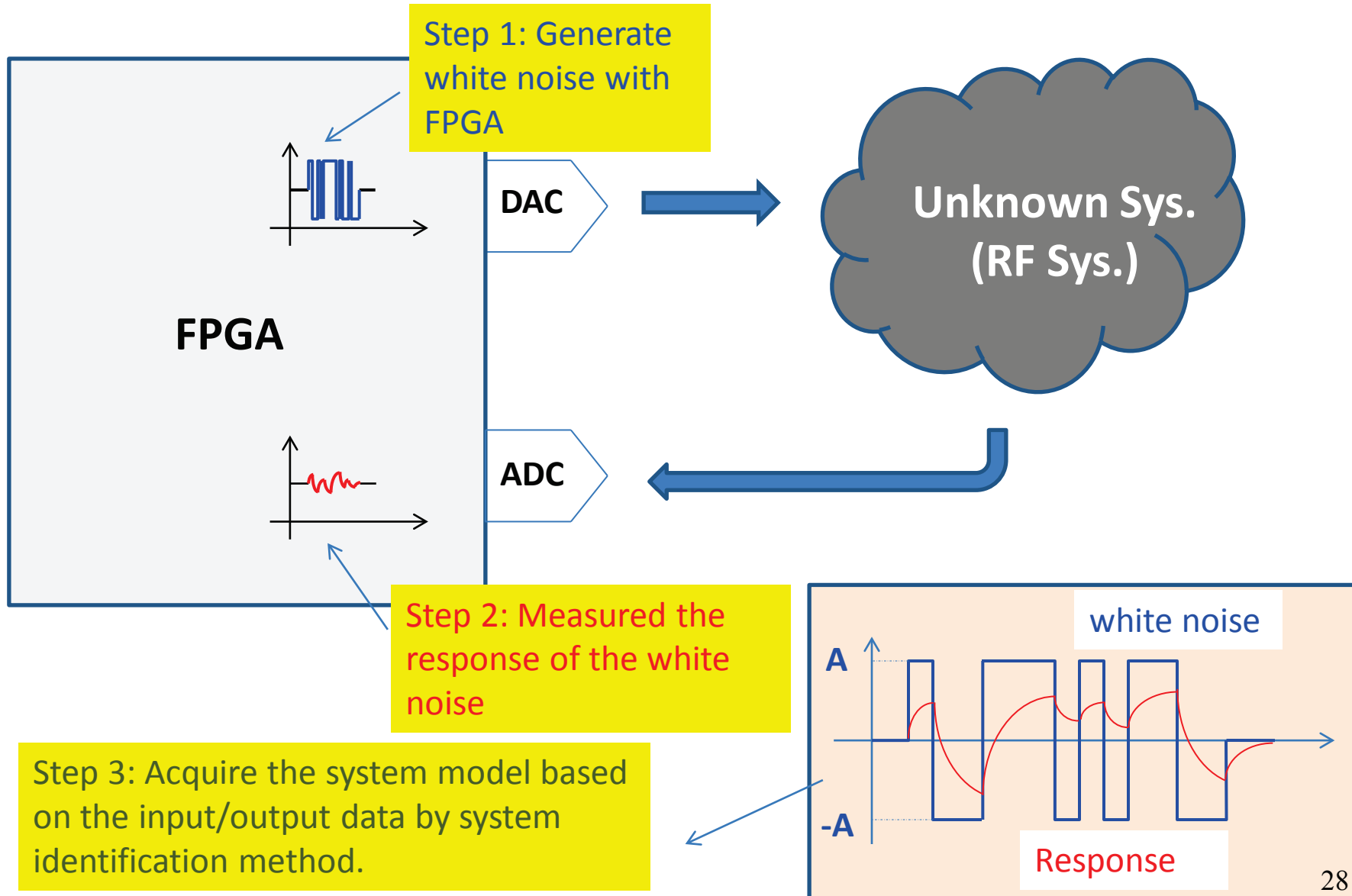
➤ PI + DOBC (AFF)



System Identification

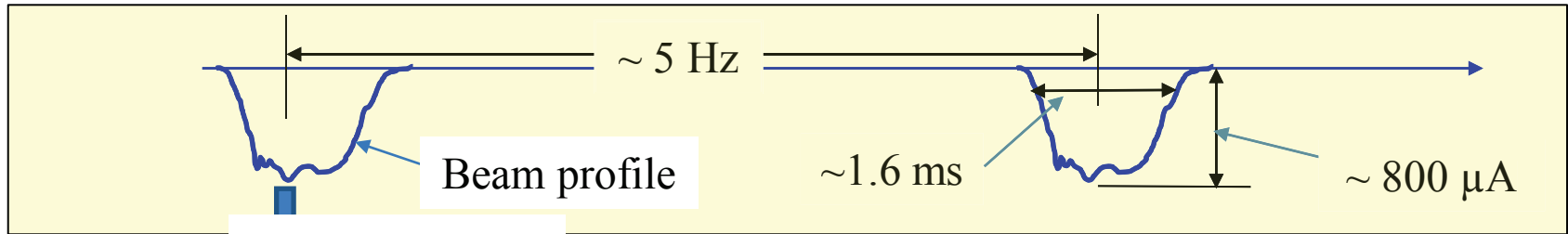


- Input white noise in the DAC output and read the response from the ADC?

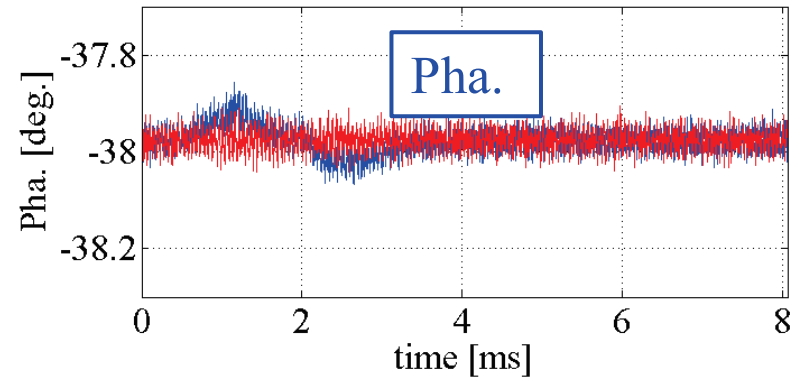
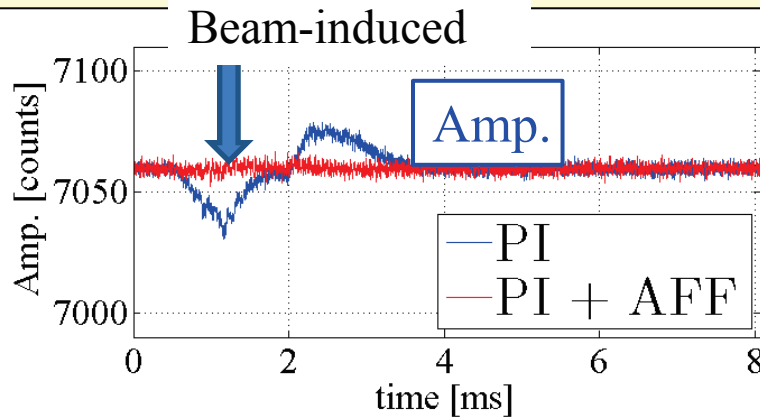


Application 2 (Beam-loading)

- Disturbances: Beam-loading (about 1.6 ms and 800 μA beam current)



Inj. 1



Inj. 2&3

